



DAC8562, DAC8563 DAC8162, DAC8163 DAC7562, DAC7563

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DUAL 16-/14-/12-BIT, ULTRALOW-GLITCH, LOW-POWER, BUFFERED, VOLTAGE-OUTPUT DAC WITH 2.5-V, 4-PPM/°C INTERNAL REFERENCE IN SMALL 3-MM × 3-MM QFN

Check for Samples: DAC8562, DAC8563, DAC8162, DAC8163, DAC7562, DAC7563

FEATURES

- Relative Accuracy:
 - DAC856x (16-Bit): 4 LSB INL
 - DAC816x (14-Bit): 1 LSB INL
 - DAC756x (12-Bit): 0.3 LSB INL
- Glitch Energy: 0.1 nV-s
- Bidirectional Reference: Input or 2.5-V Output
 - Output Disabled by Default
 - ±5-mV Initial Accuracy (Max)
 - 4-ppm/°C Temperature Drift (Typ)
 - 10-ppm/°C Temperature Drift (Max)
 - 20-mA Sink/Source Capability
- Power-On Reset to Zero Scale or Mid-Scale
- Low-Power: 4 mW (Typ, 5-V AV_{DD}, Including Internal Reference Current)
- Wide Power-Supply Range: 2.7 V to 5.5 V
- 50-MHz SPI With Schmitt-Triggered Inputs
- LDAC and CLR Functions
- Output Buffer With Rail-to-Rail Operation
- Packages: QFN-10 (3x3 mm), MSOP-10
- Temperature Range: –40°C to 125°C

APPLICATIONS

- Portable Instrumentation
- Bipolar Outputs (reference design)
- PLC Analog Output Module (reference design)
- Closed-Loop Servo Control
- Voltage Controlled Oscillator Tuning
- Data Acquisition Systems
- Programmable Gain and Offset Adjustment

DESCRIPTION

The DAC856x, DAC816x, and DAC756x are low-power, voltage-output, dual-channel, 16-, 14-, and 12-bit digital-to-analog converters (DACs), respectively. These devices include a 2.5-V, 4-ppm/°C internal reference, giving a full-scale output voltage range of 2.5 V or 5 V. The internal reference has an initial accuracy of \pm 5 mV and can source or sink up to 20 mA at the V_{REFIN}/V_{REFOUT} pin.

These devices are monotonic, providing excellent linearity and minimizing undesired code-to-code transient voltages (glitch). They use a versatile three-wire serial interface that operates at clock rates up to 50 MHz. The interface is compatible with standard SPI[™], QSPI[™], Microwire[™], and digital signal processor (DSP) interfaces. The DACxx62 devices incorporate a power-on-reset circuit that ensures the DAC output powers up at zero scale until a valid code is written to the device, whereas the DACxx63s similarly power up at mid-scale. These devices contain a power-down feature that reduces current consumption to typically 10 nA at 5 V. The low power consumption, internal reference, and small footprint make these devices ideal for portable, battery-operated equipment.

The DACxx62 devices are drop-in and function-compatible with each other, as are the DACxx63s. The entire family is available in MSOP-10 and QFN-10 packages.

Table 1. RELATED DEVICES

	16-BIT	14-BIT	12-BIT
Reset to zero	DAC8562	DAC8162	DAC7562
Reset to mid-scale	DAC8563	DAC8163	DAC7563



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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

DEVICE INFORMATION ⁽¹⁾																																																							
PRODUCT	MAXIMUM RELATIVE ACCURACY (LSB)	MAXIMUM DIFFERENTIAL NONLINEARITY (LSB)	MAXIMUM REFERENCE DRIFT (ppm/°C)	RESET TO	PACKAGE- LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPER- ATURE RANGE	PACKAGE MARKING																																															
DAC9562				Zoro	QFN-10	DSC		9560																																															
DAC6362	+12	+1	10	10	10	10	10	10	10	10	10	10	Zelo	MSOP-10	DGS	40°C to 125°C	0302																																						
DAC9562	τız	ΣI	±ι	ΞI	±Ι	±Ι	ΞI						10	10	10	10	10	Mid acolo	QFN-10	DSC	-40 C 10 125 C	9562																																	
DAC0303				wiiu-scale	MSOP-10	DGS		0303																																															
DAC0162		:3 ±0.5 10	±0.5	Zoro	QFN-10	DSC		9160																																															
DACOTOZ	12			±0.5	±0.5	±0.5	±0.5	±0.5	±0.5	±0.5	±0.5	±0.5	±0.5	10	10	10	10	Zero	MSOP-10	DGS	40°C to 425°C	0102																																	
DAC9162	13																	10	10	10	10	10	10	10	10		10	10	10	10		10		10	10		10	10	10	10		10	10	10	10	10	10	10	10	10	10	10	10	10	10
DACOTOS				wiiu-scale	MSOP-10	DGS		0103																																															
DAC7562				Zoro	QFN-10	DSC		7560																																															
DAC7562	10.75		10	10	40	10	10	10	40	10	10	10	10	10	10	10	40	10	10	10	10	40	40	10	Zero =	MSOP-10	DGS	40°C to 125°C	/ 362																										
DAC7562	±0.75 :	10.20	10	Mid coolo	QFN-10	DSC	-40 C 10 125 C	7562																																															
DAC7505				wiiu-scale	MSOP-10	DGS		1303																																															

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this data sheet, or see the TI Web site at www.ti.com.



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ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Over operating free-air temperature range (unless otherwise noted).

	VALUE	UNIT
AV _{DD} to GND	–0.3 to 6	V
CLR, DIN, LDAC, SCLK and SYNC input voltage to GND	–0.3 to AV _{DD} + 0.3	V
V _{OUT} to GND	–0.3 to AV _{DD} + 0.3	V
V _{REFIN} /V _{REFOUT} to GND	–0.3 to AV _{DD} + 0.3	V
Operating temperature range	-40 to 125	°C
Junction temperature, maximum (T _{J max})	150	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

THERMAL INFORMATION

		DAC856x, DAC	DAC856x, DAC816x, DAC756x		
	THERMAL METRIC	DSC	DGS	UNIT	
		10 PINS	10 PINS		
θ_{JA}	Junction-to-ambient thermal resistance ⁽¹⁾	62.8	173.8	°C/W	
θ _{JCtop}	Junction-to-case (top) thermal resistance ⁽²⁾	44.3	48.5	°C/W	
θ_{JB}	Junction-to-board thermal resistance ⁽³⁾	26.5	79.9	°C/W	
Ψ _{JT}	Junction-to-top characterization parameter ⁽⁴⁾	0.4	1.7	°C/W	
Ψ _{JB}	Junction-to-board characterization parameter ⁽⁵⁾	25.5	68.4	°C/W	
θ_{JCbot}	Junction-to-case (bottom) thermal resistance ⁽⁶⁾	46.2	N/A	°C/W	

(1) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.

(2) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific

JEDÉC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

(3) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.

(4) The junction-to-top characterization parameter, ψ_{JT} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).

(5) The junction-to-board characterization parameter, ψ_{JB} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).

(6) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

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ELECTRICAL CHARACTERISTICS

At AV_{DD} = 2.7 V to 5.5 V and $T_A = -40^{\circ}$ C to 125°C (unless otherwise noted).

P	ARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
STATIC PERF	ORMANCE ⁽¹⁾						
	Resolution		16			Bits	
DAC856x	Relative accuracy	Using line passing through codes 512 and 65,024		±4	±12	LSB	
	Differential nonlinearity	16-bit monotonic		±0.2	±1	LSB	
	Resolution		14			Bits	
DAC816x	Relative accuracy	Using line passing through codes 128 and 16,256		±1	±3	LSB	
	Differential nonlinearity	14-bit monotonic		±0.1	±0.5	LSB	
	Resolution		12			Bits	
DAC756x	Relative accuracy	Using line passing through codes 32 and 4,064		±0.3	±0.75	LSB	
	Differential nonlinearity	12-bit monotonic		±0.05	±0.25	LSB	
Offset error		Extrapolated from two-point line ⁽¹⁾ , unloaded		±1	±4	mV	
Offset error dri	ift			±2		μV/°C	
Full-scale erro	r	DAC register loaded with all 1s		±0.03	±0.2	% FSR	
Zero-code erro	or	DAC register loaded with all 0s		1	4	mV	
Zero-code erro	or drift			±2		μV/°C	
Gain error		Extrapolated from two-point line ⁽¹⁾ , unloaded		±0.01	±0.15	% FSR	
Gain temperat	ure coefficient			±1		ppm FSR/°C	
OUTPUT CHA	RACTERISTICS ⁽²⁾	·			1		
Output voltage	range		0		AV_{DD}	V	
Output voltage settling time ⁽³⁾		DACs unloaded		7		μs	
		$R_L = 1 M\Omega$		10			
Slew rate		Measured between 20% - 80% of a full-scale transition		0.75		V/µs	
Conscitive los	d stability	R _L = ∞		1		nF	
Capacitive load	u Stability	$R_L = 2 k\Omega$		3		ΠF	
Code-change	glitch impulse	1-LSB change around major carry		0.1		nV-s	
Digital feedthro	ough	SCLK toggling, SYNC high		0.1		nV-s	
Power-on glitc	h impulse	$R_L = 2 \text{ k}\Omega, C_L = 470 \text{ pF}, \text{AV}_{DD} = 5.5 \text{ V}$		40		mV	
Channel to sh		Full-scale swing on adjacent channel, External reference		5		μV	
Channel-to-cha		Full-scale swing on adjacent channel, Internal reference		15			
DC output imp	edance	At mid-scale input		5		Ω	
Short-circuit cu	urrent	DAC outputs at full-scale, DAC outputs shorted to GND		40		mA	
Power-up time	, including settling time	Coming out of power-down mode		50		μs	
AC PERFORM	IANCE ⁽²⁾						
DAC output no	bise density	$T_A = 25^{\circ}C$, at mid-scale input, $f_{OUT} = 1 \text{ kHz}$		90		nV/√Hz	
DAC output no	bise	$T_A = 25^{\circ}C$, at mid-scale input, 0.1 Hz to 10 Hz		2.6		μV_{PP}	
LOGIC INPUT	LOGIC INPUTS ⁽²⁾						
Input pin Leak	age current		-1	±0.1	1	μA	
Logic input LO	W voltage V _{IN} L		0		0.8	V	
Logic input HIC	GH voltage V _{IN} H		0.7 × AV _{DD}		AV_{DD}	V	
Pin capacitanc	e				3	pF	

(1) 16-bit: codes 512 and 65,024; 14-bit: codes 128 and 16,256; 12-bit: codes 32 and 4,064

(2) Specified by design or characterization

(3) Transition time between 1/4 scale and 3/4 scale including settling to within ±0.024% FSR

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ELECTRICAL CHARACTERISTICS (continued)

At AV_{DD} = 2.7 V to 5.5 V and $T_A = -40^{\circ}$ C to 125°C (unless otherwise noted).

P	ARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
REFERENCE							
External refere	ence current	External $V_{REF} = 2.5 V$ (when internal reference is disabled), all channels active using gain = 1		15		μA	
V _{REFIN} referen	ce input range		0		AV_{DD}	V	
Deference inn	utimpodonoo	Internal reference disabled, gain = 1		170		ĿО	
Reference input impedance		Internal reference disabled, gain = 2		85		K12	
REFERENCE	OUTPUT						
Output voltage)	$T_A = 25^{\circ}C$	2.495	2.5	2.505	V	
Initial accuracy	/	$T_A = 25^{\circ}C$	-5	±0.1	5	mV	
Output voltage	e temperature drift ⁽⁴⁾			4	10	ppm/°C	
Output voltage	e noise	f = 0.1 Hz to 10 Hz		12		μV _{PP}	
-		$T_A = 25^{\circ}C, f = 1 \text{ kHz}, C_L = 0 \mu F$		250			
Output voltage	e noise density av noise)	$T_A = 25^{\circ}C, f = 1 \text{ MHz}, C_L = 0 \mu F$		30		nV/√Hz	
(ingli noquone	y noice)	$T_A = 25^{\circ}C, f = 1 \text{ MHz}, C_L = 4.7 \mu F$		10			
Load regulatio	n, sourcing ⁽⁵⁾	$T_A = 25^{\circ}C$		20		µV/mA	
Load regulatio	n, sinking ⁽⁵⁾	$T_A = 25^{\circ}C$		185		µV/mA	
Output current	load capability ⁽⁶⁾			±20		mA	
Line regulation	1	$T_A = 25^{\circ}C$		50		μV/V	
Long-term stat	oility/drift (aging) ⁽⁵⁾	$T_A = 25^{\circ}C$, time = 0 to 1900 hours		100		ppm	
Thermal hysteresis ⁽⁵⁾		First cycle		200		2	
		Additional cycles		50		ррт	
POWER REQ	UIREMENTS ⁽⁷⁾						
Power supply	voltage		2.7		5.5	V	
		Normal mode, internal reference off		0.25	0.5	~ ^	
		Normal mode, internal reference on		0.8	1.3	mA	
	$AV_{DD} = 3.6 V 10 5.5 V$	Power-down modes ⁽⁸⁾		0.01	1		
		Power-down modes ⁽⁹⁾		0.01	3	μΑ	
'DD		Normal mode, internal reference off		0.2	0.4	m۸	
	$\Delta V = 2.7 V + 2.6 V$	Normal mode, internal reference on		0.73	1.3	ША	
	$AV_{DD} = 2.7 V 10 3.0 V$	Power-down modes ⁽⁸⁾		0.008	1		
		Power-down modes ⁽⁹⁾		0.008	3	μΑ	
		Normal mode, internal reference off		0.9	2.75	m\//	
	$\Lambda V = 36 V to 55 V$	Normal mode, internal reference on		2.9	7.15		
	$Av_{DD} = 3.0 \ v \ 10 \ 5.3 \ v$	Power-down modes ⁽⁸⁾		0.04	5.5		
Power		Power-down modes ⁽⁹⁾		0.04	16.5	μνν	
dissipation		Normal mode, internal reference off		0.54	1.44	m\//	
	$\Delta V_{} = 2.7 V + 2.6 V$	Normal mode, internal reference on		1.97	4.68	mvv	
	$\pi v_{DD} = 2.7 \ v \ 10 \ 3.0 \ v$	Power-down modes ⁽⁸⁾		0.02	3.6	3	
		Power-down modes ⁽⁹⁾		0.02	10.8	μνν	
TEMPERATU	RERANGE						
Specified perfo	ormance		-40		125	°C	

Internal reference output voltage temperature drift is characterized from -40°C to 125°C. (4)

(5) Explained in more detail in the Application Information section of this data sheet.

Specified by design or characterization (6)

(7) Input code = mid-scale, no load, $V_{IN}H = AV_{DD}$, and $V_{IN}L = GND$ (8) Temperature range -40° C to 105° C (9) Temperature range -40° C to 125° C

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PIN CONFIGURATIONS



(1) It is recommended to connect the thermal pad to the ground plane for better thermal dissipation.

Table 2. PIN DESCRIPTIONS

PIN		DESCRIPTION		
NAME	NO.	DESCRIPTION		
AV _{DD}	9	Power-supply input, 2.7 V to 5.5 V		
CLR	5	Asynchronous clear input. The $\overline{\text{CLR}}$ input is falling-edge sensitive. When $\overline{\text{CLR}}$ is activated, zero scale (DACxx62) or mid-scale (DACxx63) is loaded to all input and DAC registers. This sets the DAC output voltages accordingly. The part exits clear code mode on the 24 th falling edge of the next write to the part. If $\overline{\text{CLR}}$ is activated during a write sequence, the write is aborted.		
D _{IN}	8	Serial data input. Data are clocked into the 24-bit input shift register on each falling edge of the serial clock input. Schmitt-trigger logic input		
GND	3	Ground reference point for all circuitry on the device		
LDAC	4	In <i>synchronous</i> mode, data are updated with the falling edge of the 24 th SCLK cycle, which follows a falling edge of SYNC. For such <i>synchronous</i> updates, the LDAC pin is not required, and it must be connected to GND permanently or asserted and held low before sending commands to the device. In <i>asynchronous</i> mode, the LDAC pin is used as a negative edge-triggered timing signal for simultaneous DAC updates. Multiple single-channel commands can be written in order to set different channel buffers to desired values and then make a falling edge on LDAC pin to simultaneously update the DAC output registers.		
SCLK	7	Serial clock input. Data can be transferred at rates up to 50 MHz. Schmitt-trigger logic input		
SYNC	6	Level-triggered control input (active-low). This input is the frame synchronization signal for the input data. When SYNC goes low, it enables the input shift register, and data are <u>sampled</u> on subsequent falling clock edges. The DAC output updates following the 24 th clock falling edge. If SYNC is taken high before the 23 rd clock edge, the rising edge of SYNC acts as an interrupt, and the write sequence is ignored by the DAC756x/DAC816x/DAC856x. Schmitt-trigger logic input		
V _{OUT} A	1	Analog output voltage from DAC-A		
V _{OUT} B	2	Analog output voltage from DAC-B		
V _{REFIN} / V _{REFOUT}	10	Bidirectional voltage reference pin. If internal reference is used, 2.5-V output.		

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TIMING DIAGRAM



(1) Asynchronous LDAC update mode. For more information, see the LDAC Functionality section.

(2) Synchronous LDAC update mode; LDAC remains low. For more information, see the LDAC Functionality section.

Figure 1. Serial Write Operation

TIMING REQUIREMENTS⁽¹⁾⁽²⁾

At $AV_{DD} = 2.7$ V to 5.5 V and over -40° C to 125° C (unless otherwise noted).

DADAMETED		DAC756x/D	DAC756x/DAC816x/DAC856x		
	PARAMETER	MIN	ТҮР	MAX	UNIT
t ₁	SCLK falling edge to SYNC falling edge (for successful write operation)	10			ns
t2 ⁽³⁾	SCLK cycle time	20			ns
t ₃	SYNC rising edge to 23 rd SCLK falling edge (for successful SYNC interrupt)	13			ns
t ₄	Minimum SYNC HIGH time	80			ns
t ₅	SYNC to SCLK falling edge setup time	13			ns
t ₆	SCLK LOW time	8			ns
t ₇	SCLK HIGH time	8			ns
t ₈	SCLK falling edge to SYNC rising edge	10			ns
t ₉	Data setup time	6			ns
t ₁₀	Data hold time	5			ns
t ₁₁	SCLK falling edge to LDAC falling edge for asynchronous LDAC update mode	5			ns
t ₁₂	LDAC pulse duration, LOW time	10			ns
t ₁₃	CLR pulse duration, LOW time	80			ns
t ₁₄	CLR falling edge to start of VOUT transition		100		ns

(1) All input signals are specified with $t_R = t_F = 3$ ns (10% to 90% of AV_{DD}) and timed from a voltage level of (V_{IN}L + V_{IN}H)/2.

(2) See the Serial Write Operation timing diagram (Figure 1).

(3) Maximum SCLK frequency is 50 MHz at $AV_{DD} = 2.7$ V to 5.5 V.

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TABLES OF GRAPHS

Table 3. Typical Characteristics: Internal Reference Performance

MEASUREMENT	POWER-SUPPLY VOLTAGE	FIGURE NUMBER
Internal Reference Voltage vs Temperature		Figure 2
Internal Reference Voltage Temperature Drift Histogram		Figure 3
Internal Reference Voltage vs Load Current	5.5 V	Figure 4
Internal Reference Voltage vs Time		Figure 5
Internal Reference Noise Density vs Frequency		Figure 6
Internal Reference Voltage vs Supply Voltage	2.7 V – 5.5 V	Figure 7

MEASUREMENT		POWER-SUPPLY VOLTAGE	FIGURE NUMBER
FULL-SCALE, GAIN, OFFSET AND ZERO-CODE	ERRORS		
Full-Scale Error vs Temperature			Figure 16
Gain Error vs Temperature	E E V	Figure 17	
Offset Error vs Temperature		5.5 V	Figure 18
Zero-Code Error vs Temperature			Figure 19
Full-Scale Error vs Temperature			Figure 63
Gain Error vs Temperature		271	Figure 64
Offset Error vs Temperature	2.7 V	Figure 65	
Zero-Code Error vs Temperature			Figure 66
LOAD REGULATION			
DAC Output Voltage vs Load Current		5.5 V	Figure 30
		2.7 V	Figure 74
DIFFERENTIAL NONLINEARITY ERROR			1
Differential Linearity Error vs Digital Input Code	$T = -40^{\circ}C$		Figure 9
	T = 25°C	55 V	Figure 11
	T = 125°C	0.0 V	Figure 13
Differential Linearity Error vs Temperature			Figure 15
	$T = -40^{\circ}C$		Figure 56
Differential Linearity Error vs Digital Input Code	T = 25°C	27.1/	Figure 58
	T = 125°C	2.7 V	Figure 60
Differential Linearity Error vs Temperature			Figure 62
INTEGRAL NONLINEARITY ERROR (RELATIVE	ACCURACY)		1
	$T = -40^{\circ}C$		Figure 8
Linearity Error vs Digital Input Code	T = 25°C	55 V	Figure 10
	T = 125°C	5.5 V	Figure 12
Linearity Error vs Temperature			Figure 14
	$T = -40^{\circ}C$		Figure 55
Linearity Error vs Digital Input Code	T = 25°C	27.1	Figure 57
	T = 125°C	2.1 V	Figure 59
Linearity Error vs Temperature			Figure 61

Table 4. Typical Characteristics: DAC Static Performance

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MEASUREMENT		POWER-SUPPLY VOLTAGE	FIGURE NUMBER
POWER-DOWN CURRENT			
Power-Down Current vs Temperature		5.5 V	Figure 28
Power-Down Current vs Power-Supply Voltage		2.7 V – 5.5 V	Figure 29
Power-Down Current vs Temperature		2.7 V	Figure 73
POWER-SUPPLY CURRENT		·	•
Power-Supply Current vs Temperature External V _{REF} Internal V _{REF}			Figure 20
Power-Supply Current vs Temperature	Internal V _{REF}		Figure 21
Denver Surrely Correction Divited Jamest Cords	External V _{REF}	5.5.1	Figure 22
Power-Supply Current vs Digital Input Code	Internal V _{REF}	5.5 V	Figure 23
Denne Denne k. Orman k. Kista andre	External V _{REF}		Figure 24
Power-Supply Current Histogram	Internal V _{REF}		Figure 25
Denver Comple Competers Denver Comple Maltage	External V _{REF}		Figure 26
Power-Supply Current vs Power-Supply Voltage	Internal V _{REF}	2.7 V - 5.5 V	Figure 27
Dennes Street, Correction Terrestore	External V _{REF}		Figure 49
Power-Supply Current vs Temperature	Internal V _{REF}		Figure 50
Developments District Instant October	External V _{REF}	0.0.1/	Figure 51
Power-Supply Current vs Digital Input Code	Internal V _{REF}	3.6 V	Figure 52
Denver Communication	External V _{REF}		Figure 53
Power-Supply Current Histogram	Internal V _{REF}		Figure 54
	External V _{REF}		Figure 67
Power-Supply Current vs Temperature	Internal V _{REF}		Figure 68
Developments District Instant October	External V _{REF}	0.7.1/	Figure 69
Power-Supply Current vs Digital Input Code	Internal V _{REF}	2.7 V	Figure 70
Denne Denne k. Orman i likata ana a	External V _{REF}		Figure 71
Power-Supply Current Histogram	Internal VREE		Figure 72

Table 4. Typical Characteristics: DAC Static Performance (continued)

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Table 5. Typical Characteristics: DAC Dynamic Performance

ME	ASUREMENT	POWER-SUPPLY VOLTAGE	FIGURE NUMBER
CHANNEL-TO-CHANNEL CROSST	ALK		
	5-V Rising Edge	5.5.1	Figure 43
Channel-to-Channel Crosstalk	5-V Falling Edge	5.5 V	Figure 44
CLOCK FEEDTHROUGH			
	500 Hile Mide and	5.5 V	Figure 48
Clock FeedInrough	500 KHZ, MIdSCale	2.7 V	Figure 87
GLITCH ENERGY			·
	Rising Edge, Code 7FFFh to 8000h		Figure 37
Glitch Energy, 1-LSB Step	Falling Edge, Code 8000h to 7FFFh		Figure 38
	Rising Edge, Code 7FFCh to 8000h	551/	Figure 39
Glitch Energy, 4-LSB Step	Falling Edge, Code 8000h to 7FFCh	5.5 V	Figure 40
	Rising Edge, Code 7FF0h to 8000h		Figure 41
Glitch Energy, 16-LSB Step	Falling Edge, Code 8000h to 7FF0h		Figure 42
	Rising Edge, Code 7FFFh to 8000h		Figure 79
Glitch Energy, 1-LSB Step	Falling Edge, Code 8000h to 7FFFh	-	Figure 80
Glitch Energy, 4-LSB Step Glitch Energy, 16-LSB Step	Rising Edge, Code 7FFCh to 8000h		Figure 81
	Falling Edge, Code 8000h to 7FFCh	2.7 V	Figure 82
	Rising Edge, Code 7FF0h to 8000h		Figure 83
Glitch Energy, 16-LSB Step	Falling Edge, Code 8000h to 7FF0h		Figure 84
NOISE			·
DAC Output Noise Density vs	External V _{REF}		Figure 45
Frequency	Internal V _{REF}	5.5 V	Figure 46
DAC Output Noise 0.1 Hz to 10 Hz	External V _{REF}		Figure 47
POWER-ON GLITCH			
	Reset to Zero Scale		Figure 35
Devues en Olitek	Reset to Midscale	5.5 V	Figure 36
Power-on Glitch	Reset to Zero Scale	071/	Figure 85
	Reset to Midscale	2.7 V	Figure 86
SETTLING TIME			·
	Rising Edge, Code 0h to FFFFh		Figure 31
Full-Scale Settling Time	Falling Edge, Code FFFFh to 0h	5.5.1	Figure 32
	Rising Edge, Code 4000h to C000h	5.5 V	Figure 33
Hait-Scale Settling Time	Falling Edge, Code C000h to 4000h		Figure 34
	Rising Edge, Code 0h to FFFFh		Figure 75
Fuil-Scale Settling Lime	Falling Edge, Code FFFFh to 0h	0714	Figure 76
	Rising Edge, Code 4000h to C000h	2.7 V	Figure 77
Hair-Scale Settling Time	Falling Edge, Code C000h to 4000h		Figure 78



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TYPICAL CHARACTERISTICS: Internal Reference

At $T_A = 25^{\circ}$ C, $AV_{DD} = 5.5$ V, gain = 2 and V_{REFOUT} , unloaded unless otherwise noted.



Figure 2.













Figure 3.

INTERNAL REFERENCE VOLTAGE vs TIME



INTERNAL REFERENCE VOLTAGE

vs SUPPLY VOLTAGE



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TYPICAL CHARACTERISTICS: DAC at $AV_{DD} = 5.5 V$ (continued) At $T_A = 25^{\circ}C$, 5-V external reference used, gain = 1 and DAC output not loaded, unless otherwise noted.



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EXAS NSTRUMENTS

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TYPICAL CHARACTERISTICS: DAC at AV_{DD} = 5.5 V (continued)





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TYPICAL CHARACTERISTICS: DAC at AV_{DD} = 5.5 V (continued)

At $T_A = 25^{\circ}C$, 5-V external reference used, gain = 1 and DAC output not loaded, unless otherwise noted.



Figure 31.

HALF-SCALE SETTLING TIME: RISING EDGE



Figure 33.

POWER-ON GLITCH RESET TO ZERO SCALE





Figure 32.

HALF-SCALE SETTLING TIME: FALLING EDGE



POWER-ON GLITCH



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TYPICAL CHARACTERISTICS: DAC at $AV_{DD} = 5.5 V$ (continued)

At T_A = 25°C, 5-V external reference used, gain = 1 and DAC output not loaded, unless otherwise noted.



Figure 37.

GLITCH ENERGY RISING EDGE, 4-LSB STEP



Figure 39.

GLITCH ENERGY RISING EDGE, 16-LSB STEP







Figure 38.

GLITCH ENERGY FALLING EDGE, 4-LSB STEP



Figure 40.

GLITCH ENERGY FALLING EDGE, 16-LSB STEP





TYPICAL CHARACTERISTICS: DAC at AV_{DD} = 5.5 V (continued)

At $T_A = 25^{\circ}C$, 5-V external reference used, gain = 1 and DAC output not loaded, unless otherwise noted.



Figure 43.









CHANNEL-TO-CHANNEL CROSSTALK 5-V FALLING EDGE



Figure 44.

DAC OUTPUT NOISE DENSITY vs FREQUENCY





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TYPICAL CHARACTERISTICS: DAC at AV_{DD} = 2.7 V (continued)





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 TYPICAL CHARACTERISTICS: DAC at AV_{DD} = 2.7 V (continued)

 At T_A = 25°C, 2.5-V external reference used, gain = 1 and DAC output not loaded, unless otherwise noted.

 POWER-DOWN CURRENT









Figure 75.







FULL-SCALE SETTLING TIME: FALLING EDGE



Figure 76.

HALF-SCALE SETTLING TIME: FALLING EDGE



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TYPICAL CHARACTERISTICS: DAC at AV_{DD} = 2.7 V (continued)



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TYPICAL CHARACTERISTICS: DAC at $AV_{DD} = 2.7 V$ (continued)

At $T_A = 25^{\circ}C$, 2.5-V external reference used, gain = 1 and DAC output not loaded, unless otherwise noted.



Time (500 ns/div) Figure 87.



THEORY OF OPERATION

DIGITAL-TO-ANALOG CONVERTER (DAC)

The DAC756x, DAC816x, and DAC856x architecture consists of two string DACs, each followed by an output buffer amplifier. The devices include an internal 2.5-V reference with 4-ppm/°C temperature drift performance. Figure 88 shows a principal block diagram of the DAC architecture.



Figure 88. DAC Architecture

The input coding to the DAC756x, DAC816x, and DAC856x is straight binary, so the ideal output voltage is given by Equation 1:

$$V_{OUT} = \left(\frac{D_{IN}}{2^n}\right) \times V_{REF} \times Gain$$

(1)

where:

n = resolution in bits; either 12 (DAC756x), 14 (DAC816x) or 16 (DAC856x)

 D_{IN} = decimal equivalent of the binary code that is loaded to the DAC register. D_{IN} ranges from 0 to $2^n - 1$. V_{REF} = DAC reference voltage; either V_{REFOUT} from the internal 2.5-V reference or V_{REFIN} from an external reference.

Gain = 1 by default when internal reference is disabled (using external reference), and gain = 2 by default when using internal reference. Gain can also be manually set to either 1 or 2 using the gain register. See the *GAIN REGISTERS* section for more information.



Resistor String

The resistor string section is shown in Figure 89. It is simply a string of resistors, each of value *R*. The code loaded into the DAC register determines at which node on the string the voltage is tapped off to be fed into the output amplifier by closing one of the switches connecting the string to the amplifier. The resistor string architecture guarantees monotonicity. The $R_{DIVIDER}$ switch is controlled by the gain registers (see the *GAIN REGISTERS* section). Because the output amplifier has a gain of two, $R_{DIVIDER}$ is not shorted when the DAC-n gain is set to one (default if internal reference is disabled), and is shorted when the DAC-n gain is set to two (default if internal reference).



Figure 89. Resistor String

Output Amplifier

The output buffer amplifier is capable of generating rail-to-rail voltages on its output, giving a maximum output range of 0 V to AV_{DD} . It is capable of driving a load of 2 k Ω in parallel with 3 nF to GND. The typical slew rate is 0.75 V/µs, with a typical full-scale settling time of 14 µs as shown in Figure 31, Figure 32, Figure 75 and Figure 76.

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INTERNAL REFERENCE

The DAC756x, DAC816x, and DAC856x include a 2.5-V internal reference that is disabled by default. The internal reference is externally available at the V_{REFIN}/V_{REFOUT} pin. The internal reference output voltage is 2.5 V and can sink and source up to 20 mA.

A minimum 150-nF capacitor is recommended between the reference output and GND for noise filtering.

The internal reference of the DAC756x, DAC816x, and DAC856x is a bipolar transistor based precision bandgap voltage reference. Figure 90 shows the basic bandgap topology. Transistors Q_1 and Q_2 are biased such that the current density of Q_1 is greater than that of Q_2 . The difference of the two base-emitter voltages ($V_{BE1} - V_{BE2}$) has a positive temperature coefficient and is forced across resistor R_1 . This voltage is amplified and added to the base-emitter voltage of Q_2 , which has a negative temperature coefficient. The resulting output voltage is virtually independent of temperature. The short-circuit current is limited by design to approximately 100 mA.



Figure 90. Bandgap Reference Simplified Schematic



POWER-ON RESET

Power-On Reset to Zero-scale

The DAC7562, DAC8162, and DAC8562 contain a power-on-reset circuit that controls the output voltage during power up. All device registers are reset as shown in Table 6. At power up all DAC registers are filled with zeros and the output voltages of all DAC channels are set to zero volts. Each DAC channel remains that way until a valid load command is written to it. The power-on reset is useful in applications where it is important to know the state of the output of each DAC while the device is in the process of powering up. No device pin should be brought high before power is applied to the device. The internal reference is disabled by default and remains that way until a valid reference-change command is executed.

Power-On Reset to Mid-scale

The DAC7563, DAC8163, and DAC8563 contain a power-on reset circuit that controls the output voltage during power up. At power up, all DAC registers are reset to mid-scale code and the output voltages of all DAC channels are set to $V_{REFIN}/2$ volts. Each DAC channel remains that way until a valid load command is written to it. The power-on reset is useful in applications where it is important to know the state of the output of each DAC while the device is in the process of powering up. No device pin should be brought high before power is applied to the device. The internal reference is powered off/down by default and remains that way until a valid reference-change command is executed. If using an external reference, it is acceptable to power on the V_{REFIN} either at the same time as or after AV_{DD} is applied.

REGISTER		DEFAULT SETTING
DAC and input registers	DACxx62	Zero-scale
DAC and input registers	DACxx63	Mid-scale
LDAC registers	LDAC pin enabled for	or both channels
Power-down registers	DACs powered up	
Internal reference register	Internal reference di	sabled
Gain registers	Gain = 1 for both cha	annels

Table 6. DACxx62 and DACxx63 Power-On Reset Values

CLR FUNCTIONALITY

The edge-triggered CLR pin can be used to set the input and DAC registers immediately according to Table 7. When the CLR pin receives a falling edge signal the clear mode is activated and changes the DAC output voltages accordingly. The part exits clear mode on the 24th falling edge of the next write to the part. If the CLR pin receives a falling edge signal during a write sequence in normal operation, the clear mode is activated and changes the input and DAC registers immediately according to Table 7.

Table 7. Clear Mode Reset Values

DEVICE	DAC Output Entering Clear Mode
DAC8562, DAC8162, DAC7562	Zero-scale
DAC8563, DAC8163, DAC7563	Mid-scale

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SERIAL INTERFACE

The DAC756x, DAC816x, and DAC856x have a 3-wire serial interface (\overline{SYNC} , SCLK, and D_{IN} ; see the Pin Descriptions) compatible with SPI, QSPI, and Microwire interface standards, as well as most DSPs. See the Serial Write Operation timing diagram (Figure 1) for an example of a typical write sequence.

The DAC756x, DAC816x, or DAC856x input shift register is 24-bits wide, consisting of two *don't care* bits (DB23 to DB22), three command bits (DB21 to DB19), three address bits (DB18 to DB16), and 16 data bits (DB15 to DB0). The 16 data bits comprise the 16-, 14-, or 12-bit input code. All 24 bits of data are loaded into the DAC under the control of the serial clock input, SCLK. DB23 (MSB) is the first bit that is loaded into the DAC shift register. It is followed by the rest of the 24-bit word pattern, left-aligned. This configuration means that the first 24 bits of data are latched into the shift register, and any further clocking of data is ignored. When the DAC registers are being written to, the DAC756x, DAC816x, and DAC856x receive all 24 bits of data, ignore DB23 and DB22, and decode the next three bits (DB21 to DB19) in order to determine the DAC operating/control mode (see Table 8 through Table 10). Bits DB18 to DB16 are used to address DAC channels. The next 16/14/12 bits of data that follow are decoded by the DAC to determine the equivalent analog output. For more details on these and other commands (such as write to LDAC register, power down DACs, etc.), see their respective sections.

The data format is straight binary, with all 0s corresponding to 0-V output and all 1s corresponding to full-scale output. For all documentation purposes, the data format and representation used here is a true 16-bit pattern (that is, FFFFh data word for full scale) that the DAC756x, DAC816x, and DAC856x require.

The write sequence begins by bringing the \overline{SYNC} line low. Data from the D_{IN} line are clocked into the 24-bit shift register on each falling edge of SCLK. The serial clock frequency can be as high as 50 MHz, making the DAC756x, DAC816x, and DAC856x compatible with high-speed DSPs. On the 24th falling edge of the serial clock, the last data bit is clocked into the shift register and the shift register locks. Further clocking does not change the shift register data.

After receiving the 24th falling clock edge, the DAC756x, DAC816x, and DAC856x decode the three command bits and three address bits and 16/14/12 data bits to perform the required function, without waiting for a SYNC rising edge. After the 24th falling edge of SCLK is received, the SYNC line may be kept low or brought high. In either case, the minimum delay time from the 24th falling SCLK edge to the next falling SYNC edge must be met in order to begin the next cycle properly; see the Serial Write Operation timing diagram (Figure 1).

A rising edge of SYNC before the 24-bit sequence is complete resets the SPI interface; no data transfer occurs. A new write sequence starts at the next falling edge of SYNC. To assure the lowest power consumption of the device, care should be taken that the levels are as close to each rail as possible.

SYNC Interrupt

In a normal write sequence, the SYNC line stays low for at least 24 falling edges of SCLK and the addressed DAC register updates on the 24th falling edge. However, if SYNC is brought high before the 23rd falling edge, it acts as an interrupt to the write sequence; the shift register resets and the write sequence is discarded. Neither an update of the data buffer contents, DAC register contents, nor a change in the operating mode occurs (as shown in Figure 91).







Input Shift Register

The input shift register (SR) of the DAC856x, DAC816x, and DAC756x is 24 bits wide (as shown in Table 8, Table 9, and Table 10, respectively), and consists of two don't care bits (DB23 to DB22), three command bits (DB21 to DB19), three address bits (DB18 to DB16), and 16 data bits (DB15 to DB0). The 16 data bits comprise the 16-, 14-, or 12-bit input code.

Table	8. DAC856x Data Input Register Format
Address	Data

		Co	omma	nd	A	ddres	S								Da	ata							
X ⁽¹⁾	Х	C2	C1	C0	A2	A1	A0	D15 D14 D13 D12 D11 D10 D9 D8 D7 D6 D5 D4 D3 D2 D										D1	D0				
DB23	3																		DB0				

(1) X' denotes don't care bits.

Table 9. DAC816x Data Input Register Format

		Co	omma	nd	A	ddres	S							Da	ata					
Х	Х	C2	C1	C0	A2	A1	A0	D13 D12 D11 D10 D9 D8 D7 D6 D5 D4 D3 D2 D1 D0								Х	Х			
DB23	3																			DB0

Table 10. DAC756x Data Input Register Format

		Co	omma	nd	A	ddres	s						Da	ata								
Х	Х	C2	C1	C0	A2	A1	A0	D11 D10 D9 D8 D7 D6 D5 D4 D3 D2 D1 D0									Х	Х	Х	Х		
DB2	3																					DB0

The DAC856x, DAC816x, and DAC756x support a number of different load commands. The load commands are summarized in Table 11 and Table 12, and fully exhausted in Table 13.

Table 11. Commands for the DAC856x, DAC816x, and DAC756x

C2 (DB21)	C1 (DB20)	C0 (DB19)	Command
0	0	0	Write to input register n (Table 12)
0	0	1	Software LDAC, update DAC register n (Table 12)
0	1	0	Write to input register n (Table 12) and update all DAC registers
0	1	1	Write to input register n and update DAC register n (Table 12)
1	0	0	Set DAC power up/down mode
1	0	1	Software reset
1	1	0	Set LDAC registers
1	1	1	Enable/disable internal reference

Table 12. Address Select for the DAC856x, DAC816x, and DAC756x

A2 (DB18)	A1 (DB17)	A0 (DB16)	Channel (n)
0	0	0	DAC-A
0	0	1	DAC-B
0	1	0	Gain (only use with command 000)
0	1	1	Reserved
1	0	0	Reserved
1	0	1	Reserved
1	1	0	Reserved
1	1	1	DAC-A and DAC-B

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Table 13. Command Matrix for the DAC856x, DAC816x, and DAC756x

	(Comman	d		Address	6			D	ata									
DB23- DB22	C2	C1	CO	A2	A1	A0	DB15- DB6	DB5	DB4	DB3- DB2	DB1	DB0	DESCRIPTION						
				0	0	0		10	6/14/12 b	it DAC da	ata	1	Write to DAC-A input register						
X ⁽¹⁾	0	0	0	0	0	1		16	6/14/12 b	it DAC da	ata		Write to DAC-B input register						
				1	1	1		10	6/14/12 b	it DAC da	ata		Write to DAC-A and DAC-B input registers						
				0	0	0		10	6/14/12 b	it DAC da	ata		Write to DAC-A input register and update all DACs						
х	0	1	0	0	0	1		10	6/14/12 b	it DAC da	ata		Write to DAC-B input register and update all DACs						
				1	1	1		10	6/14/12 b	it DAC da	ata		Write to DAC-A and DAC-B input register and update all DACs						
				0	0	0		10	6/14/12 b	it DAC da	ata		Write to DAC-A input register and update DAC-A						
х	0	1	1	0	0	1		10	6/14/12 b	it DAC da	ata		Write to DAC-B input register and update DAC-B						
				1	1	1		10	6/14/12 b	it DAC da	ata		Write to DAC-A and DAC-B input register and update all DACs						
				0	0	0				Х			Update DAC-A						
Х	0	0	1	0	0	1				Х			Update DAC-B						
				1	1	1				Х			Update all DACs						
											0	0	Gain: DAC-B gain = 2, DAC-A gain = 2 (default with internal V_{REF})						
v	0	0	0	0		0			v		0	1	Gain: DAC-B gain = 2, DAC-A gain = 1						
^	0	U	U	0	1	0			~		1	0	Gain: DAC-B gain = 1, DAC-A gain = 2						
											1	1	Gain: DAC-B gain = 1, DAC-A gain = 1 (power-on default) Power up DAC-A						
											0	1	Power up DAC-A						
Х	1	0	0		Х		х	0	0	Х	1	0	Power up DAC-B						
											1	1	Power up DAC-A and DAC-B						
											0	1	Power down DAC-A; 1 k Ω to GND						
х	1	0	0		х		х	0	1	х	1	0	Power down DAC-B; 1 kΩ to GND						
											1	1	Power down DAC-A and DAC-B; 1 $k\Omega$ to GND						
											0	1	Power down DAC-A; 100 k Ω to GND						
Х	1	0	0		Х		х	1	0	Х	1	0	Power down DAC-B; 100 kΩ to GND						
											1	1	Power down DAC-A and DAC-B; 100 $k\Omega$ to GND						
											0	1	Power down DAC-A; Hi-Z						
х	1	0	0		х		х	1	1	х	1	0	Power down DAC-B; Hi-Z						
											1	1	Power down DAC-A and DAC-B; Hi-Z						
v	1	0	1		v				v		Х	0	Reset DAC-A and DAC-B input register and update all DACs						
^	1	0	I		^				^		Х	1	Reset all registers and update all DACs (Power-on-reset update) LDAC pin active for DAC-B and DAC-A						
											0	0							
v	1	1	0		Y				v		0	1	LDAC pin active for DAC-B; inactive for DAC-A						
^		1	0		~				~		1	0	LDAC pin inactive for DAC-B; active for DAC-A						
											1	1	LDAC pin inactive for DAC-B and DAC-A						
v	1	1	1		Y				v		Х	0	0 Disable internal reference and reset DACs to gain = 1						
^	· ·	· ·			~				~		Х	1	Enable Internal Reference & reset DACs to gain = 2						

(1) X' denotes *don't care* bits.

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GAIN REGISTERS

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The gain register controls the GAIN setting in the DAC transfer function:

$$V_{OUT} = \left(\frac{D_{IN}}{2^n}\right) \times V_{REF} \times Gain$$

(2)

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The DAC756x, DAC816x, and DAC856x have a gain register for each channel. The gain for each channel, in Equation 2, is either 1 or 2. This gain is automatically set to 2 when using the internal reference, and is automatically set to 1 when the internal reference is disabled (default). However, each channel can have either gain by setting the registers appropriately. The gain registers are accessible by using command bits = 000 and address bits = 010, and using DB1 for DAC-B and DB0 for DAC-A. See Table 13 or Table 14 and Table 15 for the full command structure. The gain registers are automatically reset to provide either gain of 1 or 2 when the internal reference is powered off or on, respectively. After the reference is powered off or on, the gain register is again accessible to change the gain.

Table 14. Gain Register Command Structure

		Co	omma	nd	A	ddres	ss									Da	ata				
Х	Х	0	0	0	0	1	0	X X X X X X X X X X X X X X X X X DAC-B											DAC-A		
DB23																					DB0

DB23

DB1/DB0	Value	Gain
DB0	0	DAC-A uses gain = 2 (default with internal reference)
	1	DAC-A uses gain = 1 (default with external reference)
DB1	0	DAC-B uses gain = 2 (default with internal reference)
	1	DAC-B uses gain = 1 (default with external reference)

Table 15. DAC-n Selection for Gain Register Command



POWER-DOWN MODES

The DAC756x, DAC816x, and DAC856x have two separate sets of power-down commands. One set is for the DAC channels and the other set is for the internal reference. The internal reference is forced to a powered down state while both DAC channels are powered down, and is only enabled if any DAC channel is also in normal mode of operation. For more information on the internal reference control, see the *INTERNAL REFERENCE ENABLE REGISTER* section.

DAC Power-Down Commands

The DAC756x, DAC816x, and DAC856x DACs use four modes of operation. These modes are accessed by setting command bits C2, C1, and C0, and power-down register bits DB5 and DB4. The command bits must be set to 100. Once the command bits are set correctly, the four different power down modes are software programmable by setting bits DB5 and DB4 in the shift register. Table 13 or Table 16 through Table 18 shows how to control the operating mode with data bits PD1 (DB5), PD0 (DB4), DB1, and DB0.

						Tab	le 1	6. D	AC F	Pow	er M	ode	Reg	jiste	r Co	omm	and	Stru	cture				
		Co	omma	ind	A	ddres	s									[Data						
Х	Х	1	0	0	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	PD1	PD0	Х	Х	DAC-B	DAC-A
DB2	3																						DB0

PD1 (DB5)	PD0 (DB4)	DAC OPERATING MODES
0	0	Power up selected DACs (normal mode, default)
0	1	Power down selected DACs 1 $k\Omega$ to GND
1	0	Power down selected DACs 100 k Ω to GND
1	1	Power down selected DACs Hi-Z to GND

Table 17. DAC-n Operating Modes

Table 18. DAC-n Selection for Operating Modes

DB1/DB0	Operating Mode
0	DAC-n does not change operating mode
1	DAC-n operating mode set to value on PD1 and PD0

It is possible to write to the DAC register/buffer of the DAC channel that is powered down. When the DAC channel is then powered up, it powers up to this new value.

The advantage of the available power-down modes is that the output impedance of the device is known while it is in power-down mode. As described in Table 17, there are three different power-down options. V_{OUT} can be connected internally to GND through a 1-k Ω resistor, a 100-k Ω resistor, or open-circuited (Hi-Z). The DAC powerdown circuitry is shown in Figure 92.



Figure 92. Output Stage



SOFTWARE RESET FUNCTION

The DAC756x, DAC816x, and DAC856x contain a software reset feature. The software reset function uses command 101. The software reset command contains two reset modes which are software-programmable by setting bit DB0 in the shift register. Table 13 and/or Table 19 and Table 20 show the available software reset commands.

Table 19. Software Reset Command Structure

		Co	omma	nd	ŀ	Addres	s		Data														
Х	Х	1	0	1	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	RST
DB2	3																						DB0

RST (DB0)	Registers Reset to Default Values
0	DAC registers Input registers
1	DAC registers Input registers LDAC registers Power-down registers Internal reference register Gain registers

Table 20. Software Reset

LDAC FUNCTIONALITY

The DAC756x, DAC816x, and DAC856x offer both a software and hardware simultaneous update and control function. The DAC double-buffered architecture has been designed so that new data can be entered for each DAC without disturbing the analog outputs.

DAC756x, DAC816x, and DAC856x data updates can be performed either in *synchronous* or in *asynchronous* mode.

In asynchronous mode, the LDAC pin is used as a negative edge-triggered timing signal for simultaneous DAC updates. Multiple single-channel writes can be done in order to set different channel buffers to desired values and then make a falling edge on LDAC pin to simultaneously update the DAC output registers. Data buffers of all channels must be loaded with desired data before an LDAC falling edge. After a high-to-low LDAC transition, all DACs are simultaneously updated with the last contents of the corresponding data buffers. If the content of a data buffer is not changed, the corresponding DAC output remains unchanged after the LDAC pin is triggered. LDAC must be returned high before the next serial command is initiated.

In <u>synchronous</u> mode, data are updated with the <u>falling</u> edge of the 24th SCLK cycle, which follows a falling edge of <u>SYNC</u>. For such synchronous updates, the <u>LDAC</u> pin is not required, and it must be connected to <u>GND</u> permanently or asserted and held low before sending commands to the device.



Alternatively, all DAC outputs can be updated simultaneously using the built-in software function of LDAC. The LDAC register offers additional flexibility and control by allowing the selection of which DAC channel(s) should be updated simultaneously when the LDAC pin is being brought low. The LDAC register is loaded with a 2-bit word (DB1 and DB0) using command bits C2, C1, and C0 (see Table 13 or Table 21). The default value for each bit, and therefore for each DAC channel, is zero. If the LDAC register bit is set to 1, it overrides the LDAC pin (the LDAC pin is internally tied low for that particular DAC channel) and this DAC channel updates synchronously after the falling edge of the 24th SCLK cycle. However, if the LDAC register bit is set to 0, the DAC channel is controlled by the LDAC pin.

The combination of software and hardware simultaneous update functions is particularly useful in applications when updating a DAC channel, while keeping the other channel unaffected; see Table 13 or Table 21 and Table 22 for more information.

							10	ine	ZI. L	-DA		gisi		onn	nanc	JOU	ucit	ne					
		Co	omma	nd	A	ddres	SS									Da	ata						
Х	Х	1	1	0	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	DAC-B	DAC-A
DB2	3																						DB0

Table 21 I DAC Register Command Structure

DB1/DB0	Value	LDAC Pin Functionality
DB0	0	DAC-A uses LDAC pin
	1	DAC-A operates in synchronous mode
DB1	0	DAC-B uses LDAC pin
	1	DAC-B operates in synchronous mode

Table 22. DAC-n Selection for LDAC Register Command

INTERNAL REFERENCE ENABLE REGISTER

The internal reference in the DAC756x, DAC816x, and DAC856x is disabled by default for debugging, evaluation purposes, or when using an external reference. The internal reference can be powered up and powered down using a serial command that requires a 24-bit write sequence, as shown in Table 23 and Table 24. The internal reference is forced to a powered down state while both DAC channels are powered down, and is only enabled if any DAC channel is in normal mode of operation in addition to using the command in Table 23. During the time that the internal reference is disabled, the DAC functions normally using an external reference. At this point, the internal reference is disconnected from the V_{REFIN}/V_{REFOUT} pin (Hi-Z output).

Enabling Internal Reference

To enable the internal reference, write the 24-bit serial command shown in Table 23. When performing a power cycle to reset the device, the internal reference is switched off (default mode). In the default mode, the internal reference is powered down until a valid write sequence is applied to power up the internal reference. However, the internal reference is forced to a disabled state while both DAC channels are powered down, and remains disabled until either DAC channel is returned to the normal mode of operation. See DAC Power-Down Commands for more information on DAC channel modes of operation.

		C	omma	nd	A	Addres	S		Data														
Х	Х	1	1	1	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	1
DB2	3																						DB0

Disabling Internal Reference

To disable the internal reference, write the 24-bit serial command shown in Table 24. When performing a power cycle to reset the device, the internal reference is disabled (default mode).

Table 24. Write	Sequence	for Disabling	Internal Reference
-----------------	----------	---------------	---------------------------

		Co	omma	nd	A	Addres	S		Data														
Х	Х	1	1	1	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	0
DB23	3																						DB0

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APPLICATION INFORMATION

INTERNAL REFERENCE

The internal reference of the DAC756x, DAC816x, and DAC856x does not require an external load capacitor for stability because it is stable without any capacitive load. However, for improved noise performance, an external load capacitor of 150 nF or larger connected to the V_{REFIN}/V_{REFOUT} output is recommended. Figure 93 shows the typical connections required for operation of the DAC756x, DAC816x, and DAC856x internal reference. A supply bypass capacitor at the AV_{DD} input is also recommended.



Figure 93. Typical Connections for Operating the DAC756x/DAC816x/DAC856x Internal Reference

Supply Voltage

The internal reference features an extremely low dropout voltage. It can be operated with a supply of only 5 mV above the reference output voltage in an unloaded condition. For loaded conditions, refer to the *Load Regulation* section. The stability of the internal reference with variations in supply voltage (line regulation, DC PSRR) is also exceptional. Within the specified supply voltage range of 2.7 V to 5.5 V, the variation at V_{REFIN}/V_{REFOUT} is typically 50 μ V/V; see Figure 7.

Temperature Drift

The internal reference is designed to exhibit minimal drift error, defined as the change in reference output voltage over varying temperature. The drift is calculated using the box method described by Equation 3:

Drift Error =
$$\left(\frac{V_{\text{REF}_MAX} - V_{\text{REF}_MIN}}{V_{\text{REF}} \times T_{\text{RANGE}}}\right) \times 10^6 (\text{ppm}/^{\circ}\text{C})$$
 (3)

where:

 V_{REF_MAX} = maximum reference voltage observed within temperature range T_{RANGE} . V_{REF_MIN} = minimum reference voltage observed within temperature range T_{RANGE} . V_{REF} = 2.5 V, target value for reference output voltage. T_{RANGE} = the characterized range from -40°C to 125°C (165°C range)

The internal reference features an exceptional typical drift coefficient of 4 ppm/°C from -40°C to 125°C. Characterizing a large number of units, a maximum drift coefficient of 10 ppm/°C is observed. Temperature drift results are summarized in Figure 3.

Noise Performance

Typical 0.1-Hz to 10-Hz voltage noise and noise spectral density performance are listed in the *Electrical Characteristics*. Additional filtering can be used to improve output noise levels, although care should be taken to ensure the output impedance does not degrade the AC performance. The output noise spectrum at the $V_{\text{REFIN}}/V_{\text{REFOUT}}$ pin, both unloaded and with an external 4.7-µF load capacitor, is shown in Figure 6. Internal reference noise impacts the DAC output noise when the internal reference is used.

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(4)

Load Regulation

Load regulation is defined as the change in reference output voltage as a result of changes in load current. The load regulation of the internal reference is measured using force and sense contacts as shown in Figure 94. The force and sense lines reduce the impact of contact and trace resistance, resulting in accurate measurement of the load regulation contributed solely by the internal reference. Measurement results are shown in Figure 4. Force and sense lines should be used for applications that require improved load regulation.



Figure 94. Accurate Load Regulation of the DAC756x/DAC816x/DAC856x Internal Reference

Long-Term Stability

Long-term stability/aging refers to the change of the output voltage of a reference over a period of months or years. This effect lessens as time progresses. The typical drift value for the internal reference is listed in the *Electrical Charateristics* and measurement results are shown in Figure 5. This parameter is characterized by powering up multiple devices and measuring them at regular intervals.

Thermal Hysteresis

Thermal hysteresis for a reference is defined as the change in output voltage after operating the device at 25°C, cycling the device through the operating temperature range, and returning to 25°C. Hysteresis is expressed by Equation 4:

$$V_{HYST} = \left[\frac{V_{REF_PRE} - V_{REF_POST}}{V_{REF_NOM}}\right] \times 10^{6} (ppm/^{\circ}C)$$

Where:

 V_{HYST} = thermal hysteresis.

 $V_{REF PRE}$ = output voltage measured at 25°C pre-temperature cycling.

 $V_{\text{REF_POST}}$ = output voltage measured after the device cycles through the temperature range of -40°C to 125°C, and returns to 25°C.

 $V_{REF NOM} = 2.5 V$, target value for reference output voltage.

DAC NOISE PERFORMANCE

Output noise spectral density at the V_{OUT}-n pin versus frequency is depicted in Figure 45 and Figure 46 for full-scale, mid-scale, and zero-scale input codes. The typical noise density for mid-scale code is 90 nV/ \sqrt{Hz} at 1 kHz. High-frequency noise can be improved by filtering the reference noise. Integrated output noise between 0.1 Hz and 10 Hz is close to 2.5 μ V_{PP} (mid-scale), as shown in Figure 47.



UP TO ±15-V BIPOLAR OUTPUT USING THE DAC8562

The DAC8562 is designed to be operate from a single power supply providing a maximum output range of AV_{DD} volts. However, the DAC can be placed in the configuration shown in Figure 95 in order to be designed into bipolar systems. Depending on the ratio of the resistor values, the output of the circuit can range anywhere from ±5 V to ±15 V. The design example below shows that the DAC is configured to have its internal reference enabled and the DAC8562 internal gain set to two, however, an external 2.5-V reference could also be used (with DAC8562 internal gain set to two).



Figure 95. Bipolar Output Range Circuit Using DAC8562

The transfer function shown in Equation 5 can be used to calculate the output voltage as a function of the DAC code, reference voltage and resistor ratio:

$$V_{OUT} = G \times V_{REFOUT} \left(2 \times \frac{D_{IN}}{65,536} - 1 \right)$$
(5)

where:

- D_{IN} = decimal equivalent of the binary code that is loaded to the DAC register, ranging from 0 to 65,535 for DAC8562 (16 bit).
- V_{REFOUT} = reference output voltage with the internal reference enabled from the DAC V_{REFIN}/V_{REFOUT} pin G = ratio of the resistors

An example configuration to generate a ± 10 -V output range is shown below in Equation 6 with G = 4 and V_{REFOUT} = 2.5 V:

$$V_{OUT} = 20 \times \frac{D_{IN}}{65,536} - 10 V$$

(6)

In this example, the range is set to ± 10 V by using a resistor ratio of four, V_{REFOUT} of 2.5 V, and DAC8562 internal gain of two. The resistor sizes must be selected keeping in mind the current sink/source capability of the DAC8562 internal reference. Using larger resistor values, for example R = 10 k Ω or larger is recommended. The op amp is selectable depending on the requirements of the system.

The DAC8562EVM and DAC7562EVM boards have the option to evaluate the bipolar output application by installing the components on the pre-placed footprints. For more information see either the DAC8562EVM or DAC7562EVM product folder.



PLC ANALOG OUTPUT MODULE USING THE DAC8562

The DAC8562 can be mated with one of TI's 0- to 20-mA voltage-to-current transmitters to create a low-cost, programmable current source for use in PLC applications. One specific example includes combining the DAC8562 with the XTR111 to create a voltage-to-current solution. The DAC output voltage generates a current, I_{SET} , which is determined by the value of the external resistor, R_{SET} . This current is internally amplified by 10 and output at the IS node. A p-channel MOSFET Q1 can be added in an application where a wide compliance voltage is required, for example, when using a high impedance load. The optional PNP transistor, Q2, along with the R4 resistor provides external current limiting in a case where the external FET is forced to low impedance. Additionally, resistors R2 and R3 can be used to scale the 3-V internal regulator to a desired voltage to power the DAC. Figure 96 shows a working 0- to 20-mA solution using one DAC8562 channel and a ±10-V voltage output using the other DAC8562 channel. For more information on the ±10-V voltage output circuit see the UP TO ±15-V BIPOLAR OUTPUT USING THE DAC8562 application.



Figure 96. 0- to 20-mA and ±10-V Outputs Using DAC8562



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MICROPROCESSOR INTERFACING

DAC756x/DAC816x/DAC856x to an MSP430 USI Interface

Figure 97 shows a serial interface between the DAC756x, DAC816x, or DAC856x and a typical MSP430 USI port such as the one found on the MSP430F2013. The port is configured in SPI master mode by setting bits 3, 5, 6, and 7 in USICTL0. The USI counter interrupt is set in USICTL1 to provide an efficient means of SPI communication with minimal software overhead. The serial <u>clock</u> polarity, source, and speed are controlled by settings in the USI clock control register (USICKCTL). The <u>SYNC</u> signal is derived from a bit-programmable pin on port 1; in this case, port line P1.4 is used. When data are to be transmitted to the DAC756x, DAC816x, or DAC856x, P1.4 is taken low. The USI transmits data in 8-bit bytes; thus, only eight falling clock edges occur in the transmit cycle. To load data to the DAC, P1.4 is left low after the first eight bits are transmitted; then, a second write cycle is initiated to transmit the second byte of data. P1.4 is taken high following the completion of the third write cycle.



NOTE: Additional pins omitted for clarity.



DAC756x/DAC816x/DAC856x to a TMS320 McBSP Interface

Figure 98 shows an interface between the DAC756x, DAC816x, or DAC856x and any TMS320 series DSP from Texas Instruments with a multi-channel buffered serial port (McBSP). Serial data are shifted out on the rising edge of the serial clock and are clocked into the DAC756x, DAC816x, or DAC856x on the falling edge of the SCLK signal.



NOTE: Additional pins omitted for clarity.

Figure 98. DAC756x/DAC816x/DAC856x to TMS320 McBSP Interface

DAC756x/DAC816x/DAC856x to an OMAP-L1x Processor

Figure 99 shows a serial interface between the DAC756x/DAC816x/DAC856x and the OMAP-L138. The transmit clock CLKx0 of the L138 drives SCLK of the DAC756x, DAC816x, or DAC856x, and the data transmit (Dx0) output drives the serial data line of the DAC. The SYNC signal is derived from the frame sync transmit (FSx0) line, similar to the TMS320 interface.



NOTE: Additional pins omitted for clarity.

Figure 99. DAC756x/DAC816x/DAC856x to OMAP-L1x Processor

TEXAS INSTRUMENTS

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LAYOUT

A precision analog component requires careful layout, adequate bypassing, and clean, well-regulated power supplies. The DAC756x, DAC816x, and DAC856x offer single-supply operation, and are often used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it is to keep digital noise from appearing at the output. As a result of the single ground pin of the DAC756x, DAC816x, and DAC856x, all return currents (including digital and analog return currents for the DAC) must flow through a single point. Ideally, GND would be connected directly to an analog ground plane. This plane would be separate from the ground connection for the digital components until they were connected at the power-entry point of the system. The power applied to AV_{DD} should be well-regulated and low noise. Switching power supplies and dc/dc converters often have high-frequency glitches or spikes riding on the output voltage. In addition, digital components can create similar high-frequency spikes as their internal logic switches states. This noise can easily couple into the DAC output voltage through various paths between the power connections and analog output. As with the GND connection, AV_{DD} should be connected to a power-supply plane or trace that is separate from the connection for digital logic until they are connected at the power-entry point. In addition, a 1-µF to 10-µF capacitor and 0.1-µF bypass capacitor are strongly recommended. In some situations, additional bypassing may be required, such as a 100-µF electrolytic capacitor or even a pi filter made up of inductors and capacitors – all designed to essentially low-pass filter the supply and remove the high-frequency noise.



PARAMETER DEFINITIONS

With the increased complexity of many different specifications listed in product data sheets, this section summarizes selected specifications related to digital-to-analog converters.

STATIC PERFORMANCE

Static performance parameters are specifications such as differential nonlinearity (DNL) or integral nonlinearity (INL). These are dc specifications and provide information on the accuracy of the DAC. They are most important in applications where the signal changes slowly and accuracy is required.

Differential Nonlinearity (DNL)

Differential nonlinearity (DNL) is defined as the maximum deviation of the real LSB step from the ideal 1 LSB step. Ideally, any two adjacent digital codes correspond to output analog voltages that are exactly one LSB apart. If the DNL is less than 1 LSB, the DAC is said to be monotonic.

Full-Scale Error

Full-scale error is defined as the deviation of the real full-scale output voltage from the ideal output voltage while the DAC register is loaded with the full-scale code (0xFFF). Ideally, the output should be $V_{REF} - 1$ LSB or $2 \times V_{REF} - 1$ LSB, depending on the DAC voltage gain. The full-scale error is expressed in percent of full-scale range (% FSR).

Full-Scale Error Drift

Full-scale error drift is defined as the change in full-scale error with a change in temperature. Full-scale error drift is expressed in units of ppm of FSR/°C.

Full-Scale Range (FSR)

Full-scale range (FSR) is the difference between the maximum and minimum analog output values that the DAC is specified to provide; typically, the maximum and minimum values are also specified. For an n-bit DAC, these values are usually given as the values matching with code 0 and $2^n - 1$.

Gain Error

Gain error is defined as the deviation in the slope of the real DAC transfer characteristic from the ideal transfer function. Gain error is expressed as a percentage of full-scale range (% FSR).

Gain Temperature Coefficient

The gain temperature coefficient is defined as the change in gain error with changes in temperature. The gain temperature coefficient is expressed in ppm of FSR/°C.

Least-Significant Bit (LSB)

The least significant bit (LSB) is defined as the smallest value in a binary coded system. The value of the LSB can be calculated by dividing the full-scale output voltage by 2ⁿ, where n is the resolution of the converter.

Monotonicity

Monotonicity is defined as a slope whose sign does not change. If a DAC is monotonic, the output changes in the same direction or remains constant for each step increase (or decrease) in the input code.

Most-Significant Bit (MSB)

The most significant bit (MSB) is defined as the largest value in a binary coded system. The value of the MSB can be calculated by dividing the full-scale output voltage by 2. Its value is one-half of full-scale.

Offset Error

The offset error is defined as the difference between actual output voltage and the ideal output voltage in the linear region of the transfer function. This difference is calculated by using a straight line defined by two codes (code 512 and code 65,024). Because the offset error is defined by a straight line, it can have a negative or positive value. Offset error is measured in mV.

Offset Error Drift

Offset error drift is defined as the change in offset error with a change in temperature. Offset error drift is expressed in $\mu V/^{\circ}C$.

Power-Supply Rejection Ratio (PSRR)

Power-supply rejection ratio (PSRR) is defined as the ratio of change in output voltage to a change in supply voltage for a full-scale output of the DAC. The PSRR of a device indicates how the output of the DAC is affected by changes in the supply voltage. PSRR is measured in decibels (dB).

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Relative Accuracy or Integral Nonlinearity (INL)

Relative accuracy or integral nonlinearity (INL) is defined as the maximum deviation between the real transfer function and a straight line passing through the endpoints of the ideal DAC transfer function. INL is measured in LSBs.

Resolution

Generally, the DAC resolution can be expressed in different forms. Specifications such as IEC 60748-4 recognize the numerical, analog, and relative resolution. The numerical resolution is defined as the number of digits in the chosen numbering system necessary to express the total number of steps of the transfer characteristic, where a step represents both a digital input code and the corresponding discrete analogue output value. The most commonly-used definition of resolution provided in data sheets is the numerical resolution expressed in bits.

Zero-Code Error

The zero-code error is defined as the DAC output voltage, when all 0s are loaded into the DAC register. Zero-code error is a measure of the difference between actual output voltage and ideal output voltage (0 V). It is expressed in mV. It is primarily caused by offsets in the output amplifier.

Zero-Code Error Drift

Zero-code error drift is defined as the change in zero-code error with a change in temperature. Zero-code error drift is expressed in $\mu V/^{\circ}C$.



DYNAMIC PERFORMANCE

Dynamic performance parameters are specifications such as settling time or slew rate, which are important in applications where the signal rapidly changes and/or high frequency signals are present.

Channel-to-Channel Crosstalk

Crosstalk in a multi-channel DAC is defined as a glitch coupled onto the output of a channel (victim) when the output of an adjacent channel (agressor) has a full-scale transition. It is calculated as the total area under the measured glitch on the victim channel at mid-scale code. It is expressed in nV-s.

Channel-to-Channel DC Crosstalk

Channel-to-channel dc crosstalk is defined as the dc change in the output level of one DAC channel in response to a change in the output of another DAC channel. It is measured with a full-scale output change on one DAC channel while monitoring another DAC channel at mid-scale. It is expressed in LSB.

Code Change/Digital-to-Analog Glitch Impulse

Digital-to-analog glitch impulse is the impulse injected into the analog output when the input code in the DAC register changes state. It is normally specified as the area of the glitch in nanovolt-seconds (nV-s), and is measured when the digital input code is changed by 1 LSB at the major carry transition.

DAC Output Noise

DAC output noise is defined as any voltage deviation of DAC output from the desired value (within a particular frequency band). It is measured with a DAC channel kept at mid-scale while filtering the output voltage within a band of 0.1 Hz to 10 Hz and measuring its amplitude peaks. It is expressed in terms of peak-to-peak voltage (V_{PP}) .

DAC Output Noise Density

Output noise density is defined as internally-generated random noise. Random noise is characterized as a spectral density (nV/\sqrt{Hz}) . It is measured by setting the DAC to mid-scale and measuring noise at the output.

Digital Feedthrough

Digital feedthrough is defined as the impulse seen at the output of the DAC from the digital inputs of the DAC. It is measured when the DAC output is not updated. It is specified in nV-s, and measured with a full-scale code change on the data bus; that is, from all 0s to all 1s and vice versa.

Output Voltage Settling Time

Settling time is the total time (including slew time) for the DAC output to settle within an error band around its final value after a change in input. Settling times are specified to within $\pm 0.024\%$ FSR (or whatever value is stated) of full-scale range.

Slew Rate

The output slew rate (SR) of an amplifier or other electronic circuit is defined as the maximum rate of change of the output voltage for all possible input signals.

$$SR = \max\left[\left|\frac{\Delta V_{OUT}(t)}{\Delta t}\right|\right]$$

(7)

Where $\Delta V_{OUT}(t)$ is the output produced by the amplifier as a function of time t.



21-Jul-2011

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
DAC7562SDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC7562SDGST	ACTIVE	MSOP	DGS	10	250	TBD	Call TI	Call TI	
DAC7562SDSCR	ACTIVE	SON	DSC	10	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC7562SDSCT	ACTIVE	SON	DSC	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC7563SDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC7563SDGST	ACTIVE	MSOP	DGS	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC7563SDSCR	ACTIVE	SON	DSC	10	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC7563SDSCT	ACTIVE	SON	DSC	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8162SDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8162SDGST	ACTIVE	MSOP	DGS	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8162SDSCR	ACTIVE	SON	DSC	10	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8162SDSCT	ACTIVE	SON	DSC	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8163SDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8163SDGST	ACTIVE	MSOP	DGS	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8163SDSCR	ACTIVE	SON	DSC	10	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8163SDSCT	ACTIVE	SON	DSC	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8562SDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	



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Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
DAC8562SDGST	ACTIVE	MSOP	DGS	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8562SDSCR	ACTIVE	SON	DSC	10	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8562SDSCT	ACTIVE	SON	DSC	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8563SDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8563SDGST	ACTIVE	MSOP	DGS	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8563SDSCR	ACTIVE	SON	DSC	10	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
DAC8563SDSCT	ACTIVE	SON	DSC	10	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DAC7562SDGSR	MSOP	DGS	10	2500	330.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC7562SDSCR	SON	DSC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC7562SDSCT	SON	DSC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC7563SDGSR	MSOP	DGS	10	2500	330.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC7563SDGST	MSOP	DGS	10	250	180.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC7563SDSCR	SON	DSC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC7563SDSCT	SON	DSC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC8162SDGSR	MSOP	DGS	10	2500	330.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC8162SDGST	MSOP	DGS	10	250	180.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC8162SDSCR	SON	DSC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC8162SDSCT	SON	DSC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC8163SDGSR	MSOP	DGS	10	2500	330.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC8163SDGST	MSOP	DGS	10	250	180.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC8163SDSCR	SON	DSC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC8163SDSCT	SON	DSC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC8562SDGSR	MSOP	DGS	10	2500	330.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC8562SDGST	MSOP	DGS	10	250	180.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC8562SDSCR	SON	DSC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

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Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DAC8562SDSCT	SON	DSC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC8563SDGSR	MSOP	DGS	10	2500	330.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC8563SDGST	MSOP	DGS	10	250	180.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
DAC8563SDSCR	SON	DSC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
DAC8563SDSCT	SON	DSC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
DAC7562SDGSR	MSOP	DGS	10	2500	370.0	355.0	55.0
DAC7562SDSCR	SON	DSC	10	3000	346.0	346.0	29.0
DAC7562SDSCT	SON	DSC	10	250	190.5	212.7	31.8
DAC7563SDGSR	MSOP	DGS	10	2500	370.0	355.0	55.0
DAC7563SDGST	MSOP	DGS	10	250	220.0	205.0	50.0
DAC7563SDSCR	SON	DSC	10	3000	346.0	346.0	29.0
DAC7563SDSCT	SON	DSC	10	250	190.5	212.7	31.8
DAC8162SDGSR	MSOP	DGS	10	2500	370.0	355.0	55.0
DAC8162SDGST	MSOP	DGS	10	250	220.0	205.0	50.0
DAC8162SDSCR	SON	DSC	10	3000	346.0	346.0	29.0
DAC8162SDSCT	SON	DSC	10	250	190.5	212.7	31.8
DAC8163SDGSR	MSOP	DGS	10	2500	370.0	355.0	55.0

PACKAGE MATERIALS INFORMATION



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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
DAC8163SDGST	MSOP	DGS	10	250	220.0	205.0	50.0
DAC8163SDSCR	SON	DSC	10	3000	346.0	346.0	29.0
DAC8163SDSCT	SON	DSC	10	250	190.5	212.7	31.8
DAC8562SDGSR	MSOP	DGS	10	2500	370.0	355.0	55.0
DAC8562SDGST	MSOP	DGS	10	250	220.0	205.0	50.0
DAC8562SDSCR	SON	DSC	10	3000	346.0	346.0	29.0
DAC8562SDSCT	SON	DSC	10	250	190.5	212.7	31.8
DAC8563SDGSR	MSOP	DGS	10	2500	370.0	355.0	55.0
DAC8563SDGST	MSOP	DGS	10	250	220.0	205.0	50.0
DAC8563SDSCR	SON	DSC	10	3000	346.0	346.0	29.0
DAC8563SDSCT	SON	DSC	10	250	190.5	212.7	31.8

DGS (S-PDSO-G10)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-187 variation BA.



MECHANICAL DATA



 \triangle The package thermal pad must be soldered to the board for thermal and mechanical performance.

E. See the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.



DSC (S-PWSON-N10)

PLASTIC SMALL OUTLINE NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.







NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



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